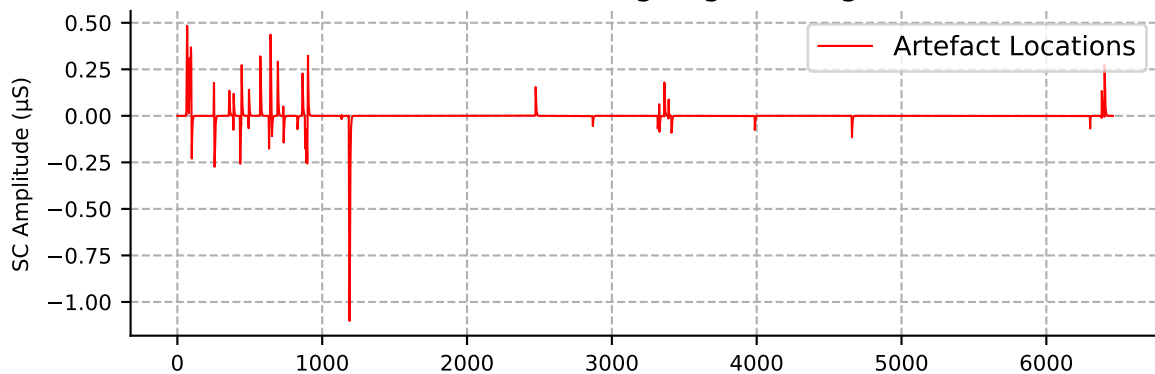


a)

EDA Artefact Locations using Logistic Regression Method

**b)**

Logistic Regression Filtered EDA

